nexperia

Reliability Monitoring Results

Quarters: Q1/2022 to Q4/2022

Based on structural similarity

Suppli	ier	User Part Number						
Nexper	ia B.V.	74AUP1G132GX	74AUP1G132GX					
Part D	Description: Single 2-input I	NAND gate Schmitt-trigger						
Pro	nction Family: AUP ocess family: C075 ckage family: X2SON					#		
JESD4	17 Test	Test Conditions	Duration	# Lots	# Quantity	Rejects		
# 1	TEST Pre- and Post-Stress Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below		
# 2	PC Preconditioning	JESD22-A113 MSL 1	N/A	1898	65792	0		
# 5a	HTOL EFR High Temperature Operating Life Extrinsic	JESD22-A108 Tj = 150°C V _{CCMAX} \leq V \leq 1.2*V _{CCMAX}	48 hours or 168 hours	240	41981	0		
# 5b	HTOL IFR High Temperature Operating Life Intrinsic	JESD22-A108 Tj = 150°C V _{CCMAX} \leq V \leq 1.2*V _{CCMAX}	≥500 hours	99	7448	0		
# 7	TC Temperature Cycling	JESD22-A104 -65 °C to 150°C	≥500 cycles	954	33368	0		
# 9	uHAST / HAST unbiased or biased High Accelerated Stress Test	JESD22-A101 Tamb = 130 °C, RH = 85%, V = V _{CCMAX}	96 hours	945	32424	0		

Calculation of PPM, FIT and MTTF

Test considered for PPM calculation: High Temperature Operating LifeTest Extrinsic (HTOL EFR, Test # 5a above) Test considered for FIT and MTTF calculations: High Temperature Operating LifeTest Intrinsic(HTOL IFR, Test # 5b above)

Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Product Family	Package Family	Quantity	Rejects	Extrinsic Failure Rate (PPM)	Intrinsic Failure Rate (FIT)	MTTF (hrs)
AUP	X2SON	7448	0	22	0.6	1.83 E+09

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